



INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Complete if known

Sheet	1	of	3	Application Number	10/672,958
				Filing Date	September 24, 2003
				First Named Inventor	Karl A. Hanold
				Group Art Unit	2881
				Examiner Name	Unknown
				Attorney Docket Number	155692-0034 (P002X2)

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code			
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Examiner: William A. J. Smith Date Considered: 3-18-05

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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		Office	Number	Kind Code			

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
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Examiner:

Shulpa Ind

Date Considered:

3-12-05

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